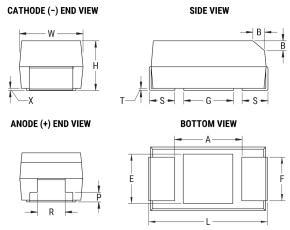


T493B105K025BH6110

T493 HRA, Tantalum, MnO2 Tantalum, HRA, 1 uF, 10%, 25 VDC, SMD, MnO2, Molded, High Reliability, B $(0.1\%/1000 \, \text{Hrs})$, 5 Ohms, 3528, Height Max = 2.1mm



Click here for the 3D model.

Dimensions		
Footprint	3528	
L	3.5mm +/-0.2mm	
W	2.8mm +/-0.2mm	
Н	1.9mm +/-0.2mm	
Т	0.13mm REF	
S	0.8mm +/-0.3mm	
F	2.2mm +/-0.1mm	
Α	1.9mm MIN	
В	0.4mm +/-0.15mm	
E	2.2mm REF	
G	1.8mm REF	
Р	0.35mm MIN	
R	1mm REF	
Χ	0.1mm +/-0.1mm	

Packaging Specifications	
Packaging	T&R, 178mm
Packaging Quantity	2000

General Information		
Series	T493 HRA	
Dielectric	MnO2 Tantalum	
Style	SMD Chip	
Description	SMD, MnO2, Molded, High Reliability	
Features	High Reliability	
RoHS	No	
Prop 65	▲ WARNING: Cancer and reproductive harm - http://www.p65warnings.ca.gov.	
SCIP Number	1dd2e1b8-26dd-4d52-927c-6f9d519011aa	
Termination	Solder Coated	
AEC-Q200	No	
Component Weight	102.3 mg	
Notes	P and R dimensions represents the minimum solderable area of the termination surface entirely below cutout (if one is present).	

Specifications	
Capacitance	1uF
Capacitance Tolerance	10%
Voltage DC	25 VDC (85C), 16.75 VDC (125C)
Temperature Range	-55/+125°C
Rated Temperature	85°C
Dissipation Factor	4% 120Hz 25C
Failure Rate	B (0.1%/1000 Hrs)
Resistance	5 Ohms (100kHz 25C)
Ripple Current	122 mA (rms, 100kHz 25C)
Leakage Current	0.5 uA (5min 25°C)
Testing and Reliability	Standard Testing Only

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.